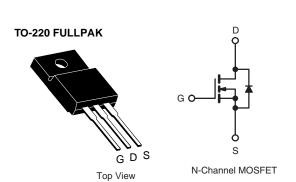


HALOGEN FREE

# N-Channel 650 V (D-S) Power MOSFET

PRODUCT SUMMA	RY	
V <sub>DS</sub> (V) at T <sub>J</sub> max.	65	50
R <sub>DS(on)</sub> at 25 °C (Ω)	V <sub>GS</sub> = 10 V	0.280
Q <sub>g</sub> max. (nC)	98	
Q <sub>gs</sub> (nC)	13	
Q <sub>gd</sub> (nC)	22	
Configuration	Sing	le



### **FEATURES**

- · Optimal Design
  - Low Area Specific On-Resistance
  - Low Input Capacitance (Ciss)
  - Reduced Capacitive Switching Losses
  - High Body Diode Ruggedness
  - Avalanche Energy Rated (UIS)
- Optimal Efficiency and Operation
  - Low Cost
  - Simple Gate Drive Circuitry
  - Low Figure-Of-Merit (FOM): Ron x Qa
  - Fast Switching

### **APPLICATIONS**

- Consumer Electronics
  - Displays (LCD or Plasma TV
- Server and Telecom Power Supplies
  - SMPS
- Industrial
  - Welding, Induction Heating, Motor Drives
- · Battery Chargers

ABSOLUTE MAXIMUM RATINGS ( $T_{\text{C}}$	= 25 °C, unle	ess otherwis	se noted)		
PARAMETER			SYMBOL	LIMIT	UNIT
Drain-Source Voltage			$V_{DS}$	650	
Gate-Source Voltage			V	± 30	V
Gate-Source Voltage AC (f > 1 Hz)			$V_{GS}$	30	
Continuous Dunis Comment /T 150 °C)	V <sub>GS</sub> at 10 V	$V = T_C = 25 \degree C$ $T_C = 100 \degree C$		22	
Continuous Drain Current (T <sub>J</sub> = 150 °C)	V <sub>GS</sub> at 10 V	T <sub>C</sub> = 100 °C	ID	14	A
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	67	1
Linear Derating Factor				2.5	W/°C
Single Pulse Avalanche Energy <sup>b</sup>			E <sub>AS</sub>	139	mJ
Maximum Power Dissipation			$P_{D}$	212	W
Operating Junction and Storage Temperature Range	е		T <sub>J</sub> , T <sub>stg</sub>	- 55 to + 150	°C
Drain-Source Voltage Slope	$T_J = 1$	25 °C	dV/dt	24	1//20
Reverse Diode dV/dt <sup>d</sup>	•		av/at	0.38	- V/ns
Soldering Recommendations (Peak Temperature)	for 1	10 s		300°	°C

#### Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature.
- b.  $V_{DD}$  = 50 V, starting  $T_J$  = 25 °C, L = 2.3 mH,  $R_g$  = 25  $\Omega$ ,  $I_{AS}$  = 11 A.
- c. 1.6 mm from case.
- d.  $I_{SD} \le I_D$ ,  $dI/dt = 100 \text{ A/}\mu\text{s}$ , starting  $T_J = 25 \,^{\circ}\text{C}$ .



THERMAL RESISTANCE RATI	NGS			
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	40	°C/W
Maximum Junction-to-Case (Drain)	$R_{thJC}$	-	0.4	G/ <b>VV</b>

<b>SPECIFICATIONS</b> (T <sub>J</sub> = 25 °C, ulparameter	SYMBOL		TOONDITIONS	BAINI	TVD	MAN	
	SYMBOL	IES	T CONDITIONS	MIN.	TYP.	MAX.	UNIT
Static		1			ı	ı	
Drain-Source Breakdown Voltage	$V_{DS}$	V <sub>GS</sub> :	= 0 V, I <sub>D</sub> = 250 μA	650	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	to 25 °C, I <sub>D</sub> = 250 μA	-	0.6	-	V/°C
Gate-Source Threshold Voltage (N)	$V_{GS(th)}$	V <sub>DS</sub> =	$= V_{GS}, I_D = 250 \mu A$	3	-	5	V
Gate-Source Leakage	$I_{GSS}$		$V_{GS} = \pm 30 \text{ V}$	-	-	± 100	nA
Zero Gate Voltage Drain Current	I <sub>DSS</sub>		= 650 V, V <sub>GS</sub> = 0 V V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C	-	-	1 10	μA
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 11 A	_	0.280	-	Ω
Forward Transconductance	9 <sub>fs</sub>	V <sub>DS</sub>	= 50 V, I <sub>D</sub> = 11 A	-	8	-	S
Dynamic							
Input Capacitance	C <sub>iss</sub>	$V_{GS} = 0 \text{ V},$ $V_{DS} = 100 \text{ V},$ f = 1  MHz		-	1938	-	pF
Output Capacitance	C <sub>oss</sub>			-	169	-	
Reverse Transfer Capacitance	C <sub>rss</sub>			-	18	-	
Effective Output Capacitance, Energy Related <sup>a</sup>	C <sub>o(er)</sub>	$V_{DS} = 0 \text{ V to } 520 \text{ V}, V_{GS} = 0 \text{ V}$		-	144	-	
Effective Output Capacitance, Time Related <sup>b</sup>	C <sub>o(tr)</sub>			-	210	-	
Total Gate Charge	Qg			-	49	98	
Gate-Source Charge	$Q_{gs}$	V <sub>GS</sub> = 10 V I <sub>D</sub> = 11 A, V <sub>DS</sub> = 400 V	-	13	-	nC	
Gate-Drain Charge	$Q_{gd}$			ı	22		-
Turn-On Delay Time	t <sub>d(on)</sub>	$V_{DD} = 480 \text{ V}, I_{D} = 11 \text{ A}, V_{GS} = 10 \text{ V}, R_{g} = 4.7 \Omega$		-	21	42	ns
Rise Time	t <sub>r</sub>			-	42	84	
Turn-Off Delay Time	t <sub>d(off)</sub>			-	47	94	
Fall Time	t <sub>f</sub>			-	40	80	
Gate Input Resistance	R <sub>g</sub>	f = 1 MHz, open drain		-	1.4	-	Ω
<b>Drain-Source Body Diode Characteristic</b>	s						
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	-	22	_
Pulsed Diode Forward Current	I <sub>SM</sub>			-	-	88	A
Diode Forward Voltage	V <sub>SD</sub>	T <sub>J</sub> = 25 °C, I <sub>S</sub> = 11 A, V <sub>GS</sub> = 0 V		-	-	1.2	V
Reverse Recovery Time	t <sub>rr</sub>	T <sub>J</sub> = 25 °C, I <sub>F</sub> = I <sub>S</sub> = 11 A, dl/dt = 100 A/µs, V <sub>R</sub> = 20 V		-	384	-	ns
Reverse Recovery Charge	Q <sub>rr</sub>			-	4.7	-	μC
Reverse Recovery Current	I <sub>RRM</sub>			-	23	-	Α

- a.  $C_{oss(er)}$  is a fixed capacitance that gives the same energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ . b.  $C_{oss(tr)}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ .



## TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

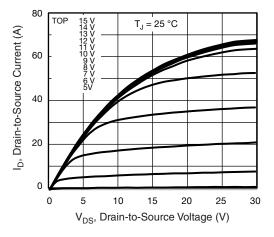


Fig. 1 - Typical Output Characteristics

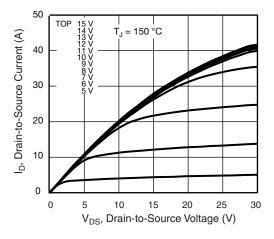


Fig. 2 - Typical Output Characteristics

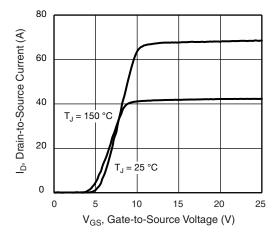


Fig. 3 - Typical Transfer Characteristics

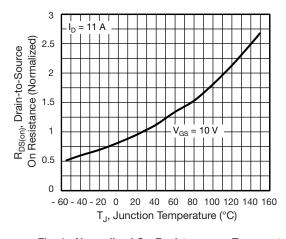


Fig. 4 - Normalized On-Resistance vs. Temperature

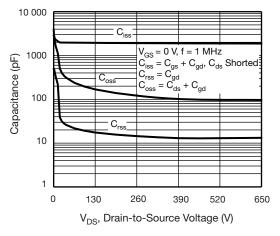


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

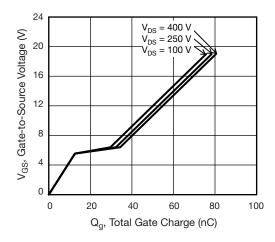


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

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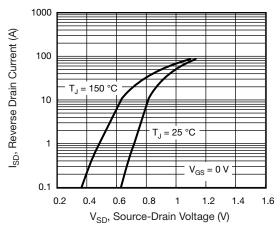


Fig. 7 - Typical Source-Drain Diode Forward Voltage

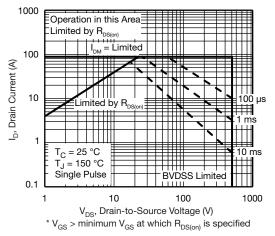


Fig. 8 - Maximum Safe Operating Area

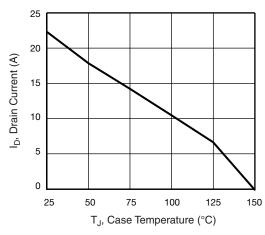


Fig. 9 - Maximum Drain Current vs. Case Temperature

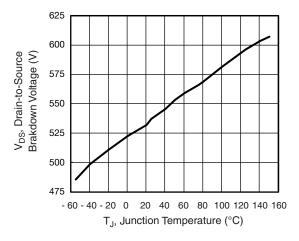


Fig. 10 - Temperature vs. Drain-to-Source Voltage

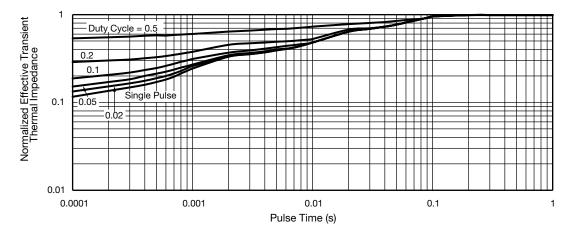


Fig. 11 - Normalized Thermal Transient Impedance, Junction-to-Case



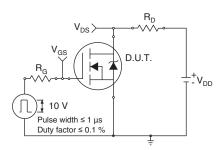


Fig. 12 - Switching Time Test Circuit

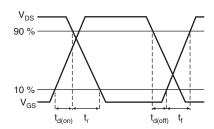


Fig. 13 - Switching Time Waveforms

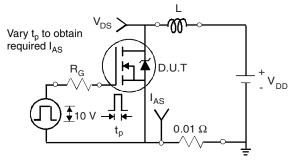


Fig. 14 - Unclamped Inductive Test Circuit

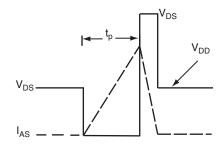


Fig. 15 - Unclamped Inductive Waveforms

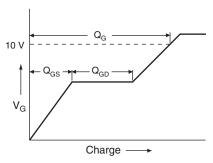


Fig. 16 - Basic Gate Charge Waveform

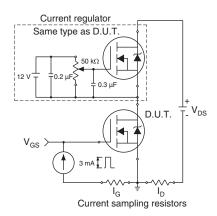
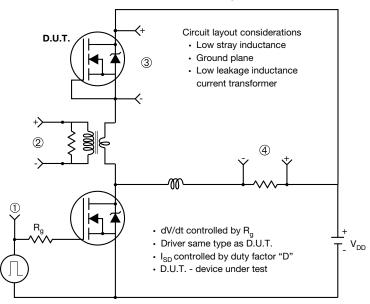


Fig. 17 - Gate Charge Test Circuit

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## Peak Diode Recovery dV/dt Test Circuit



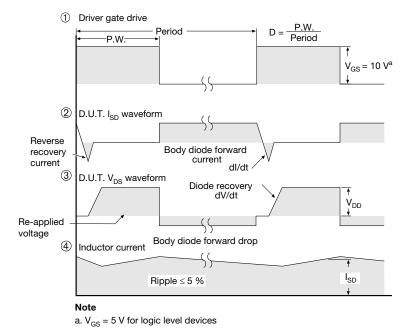
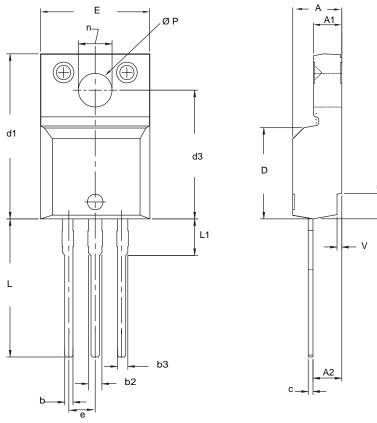


Fig. 18 - For N-Channel



## **TO-220 FULLPAK (HIGH VOLTAGE)**



DIM.	MILLIN	METERS	INCHES		
	MIN.	MAX.	MIN.	MAX.	
Α	4.570	4.830	0.180	0.190	
A1	2.570	2.830	0.101	0.111	
A2	2.510	2.850	0.099	0.112	
b	0.622	0.890	0.024	0.035	
b2	1.229	1.400	0.048	0.055	
b3	1.229	1.400	0.048	0.055	
С	0.440	0.629	0.017	0.025	
D	8.650	9.800	0.341	0.386	
d1	15.88	16.120	0.622	0.635	
d3	12.300	12.920	0.484	0.509	
E	10.360	10.630	0.408	0.419	
е	2.54	BSC	0.100 BSC		
L	13.200	13.730	0.520	0.541	
L1	3.100	3.500	0.122	0.138	
n	6.050	6.150	0.238	0.242	
ØΡ	3.050	3.450	0.120	0.136	
u	2.400	2.500	0.094	0.098	
V	0.400	0.500	0.016	0.020	

ECN: X09-0126-Rev. B, 26-Oct-09 DWG: 5972

- To be used only for process drawing.
   These dimensions apply to all TO-220, FULLPAK leadframe versions 3 leads.
   All critical dimensions should C meet C<sub>pk</sub> > 1.33.
   All dimensions include burrs and plating thickness.

- 5. No chipping or package damage.



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